



Development of THz Devices With Electron Beam Lithography

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UNIVERSITÄT
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ESSEN

Offen im Denken

Center for Semiconductor and Optoelectronics (ZHO)



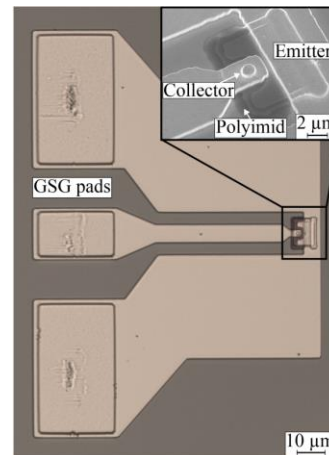
Introduction to ZHO

- Own clean room, work area~ 469 m², class 10
- Epitaxy: 2 MOCVDs, 1 MBE, InP/GaN based epilayer
- Lithography: JEOL 8100FS 100 kV system/ MJB6
- Metal Deposition: 2 electron beam deposition , 1 sputter
- Inspection: Zeiss LSM900 / JEOL IT800i
- CVD/ ALD/ RIE ICP/ Packaging
- High frequency measurement labor
- > 20 staffs

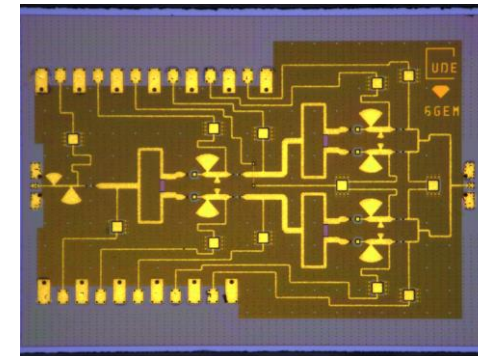


Research Focus: high frequency electronics

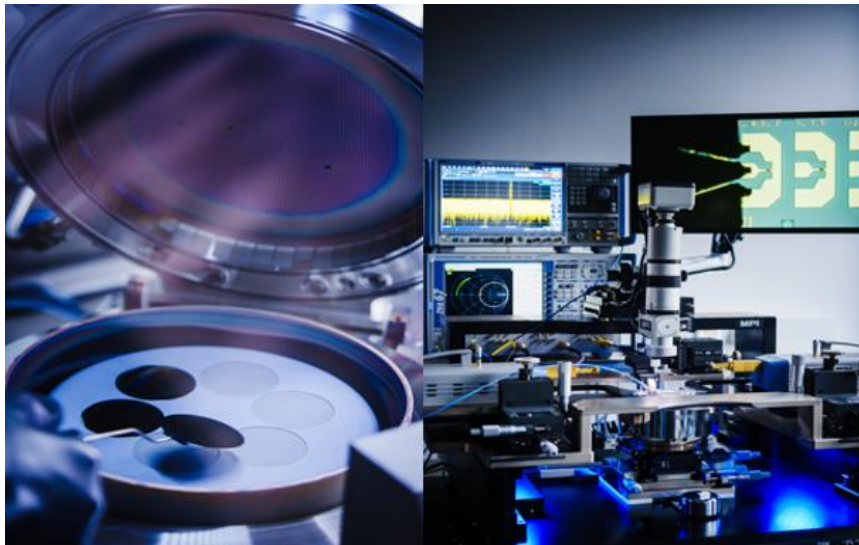
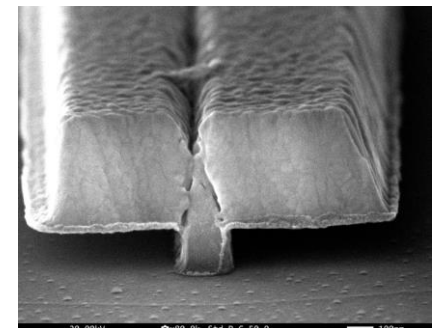
Tunneling Barrier Diode (RTD)



Double Hetrojunction Bipolar Transistor (DHBT)



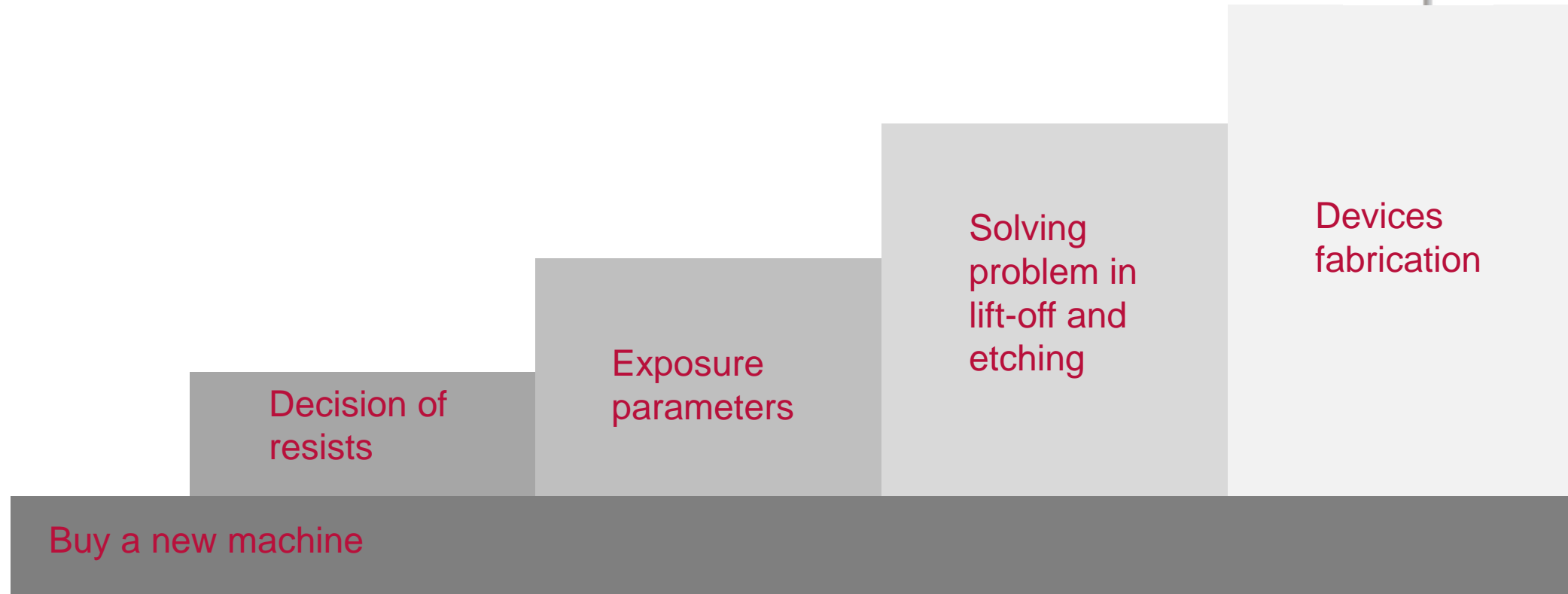
High Electron Mobility Transistor (HEMT)



Copyright: FORLAB Project

Scope of this work

Focus: InP based DHBT





JEOL 8100FS in BHE:

- The second machine in Germany
- Installed beginn 2023
- Acceleration voltage 100 kV system
- Beam current up to 200 nA
- Stage positioning resolution about 0.6 nm
- Resolution in sub 10 nm
- Load wafer up to 8 inch
- Successful exposure parameters and techniques for InP/Sapphier/Si-based devices

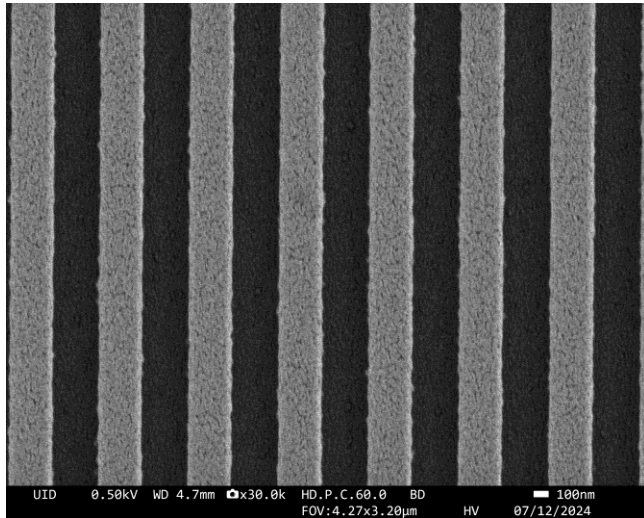
Photoresist used in BHE for nano fabrication

| Resist | Dose [$\mu\text{C}/\text{cm}^2$] | Tone | Resolution | Benefits | Contrast |
|-------------|------------------------------------|----------|------------|-------------------------------|----------|
| PMMA series | 640-800-1000 | positiv | ~5-10 nm | Less expensive | ~ 2 |
| maN 2410 | 140 | negativ | ~50-100 | Easy removed with Aceton | < 1 |
| CSAR series | 200-300 | positive | ~5 nm | Good etch resistance | 6-7 |
| ZEP520A | 100-200 | positive | ~5 nm | Much faster than PMMA | 6-7 |
| PMGI series | Not sensitiv to e^- | - | - | Very good for Bi-or Tri-layer | - |

What is the base dose?

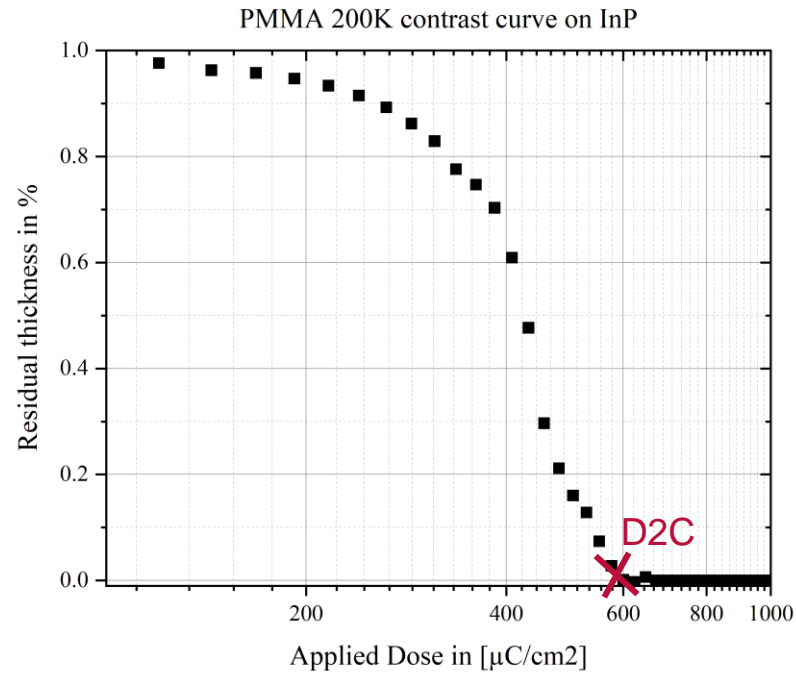
The dose in the machine, when combined with the dose factor and base dose, allows one to obtain the design pattern after processing.

The most used method is using line/space structure (50%/50%)



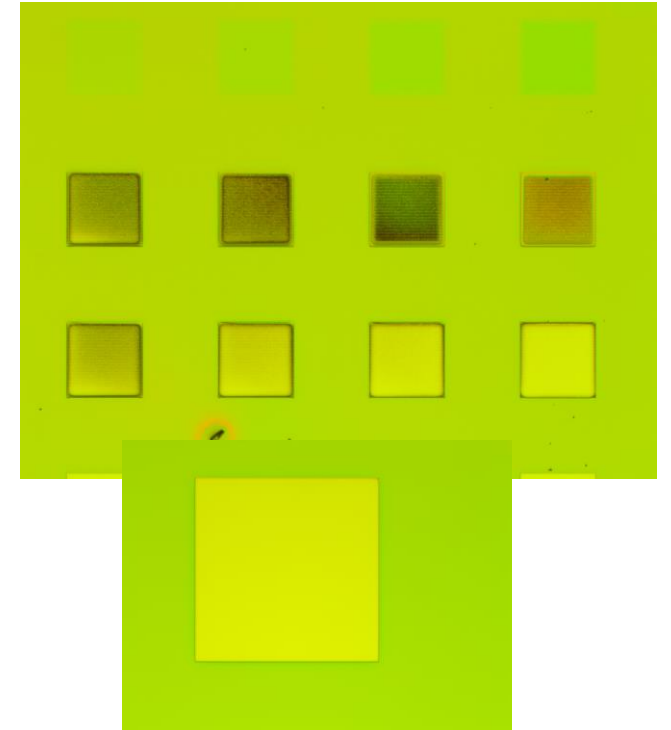
- The base dose is: $CD_{line} = CD_{space}$
- Valid only for thin and high contrast resist
- Process bias is not considered

Using contrast curve



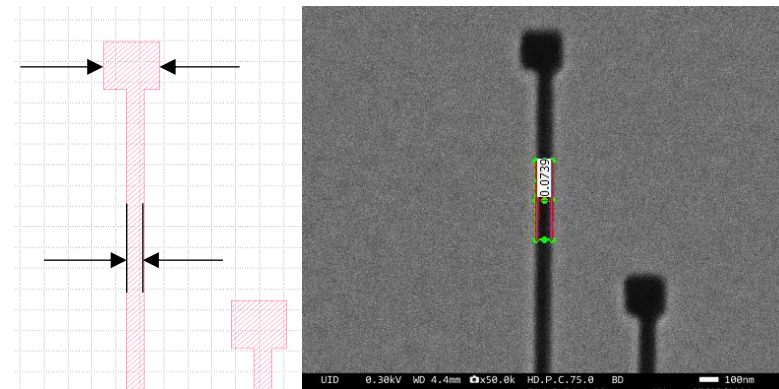
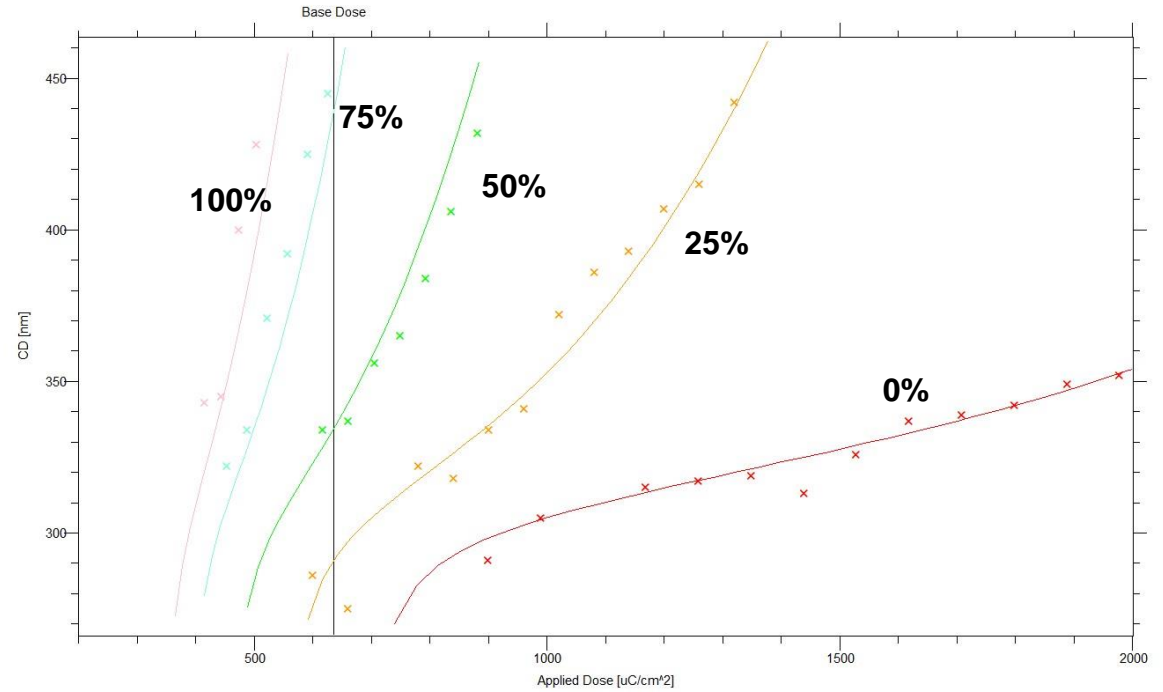
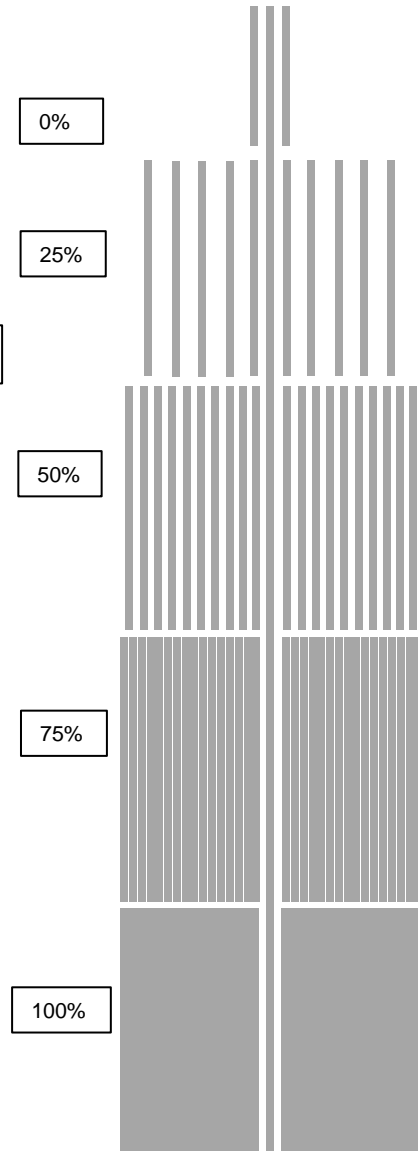
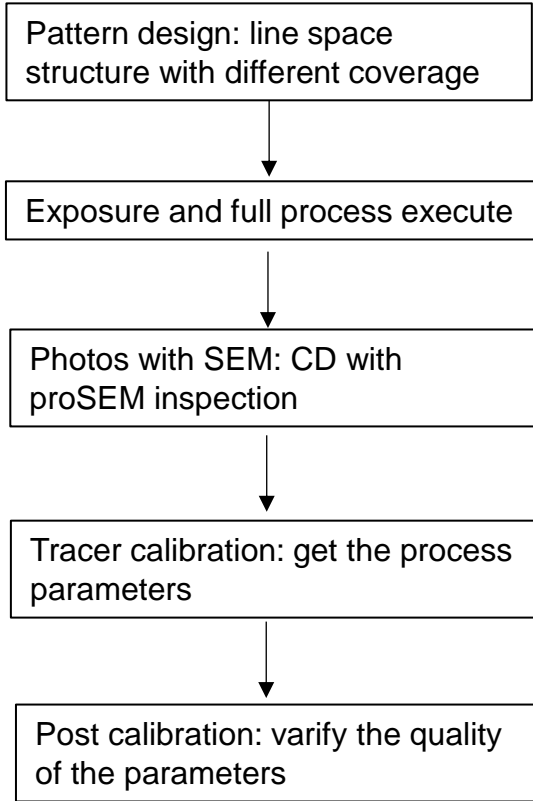
- The base dose is 2x dose to clear
- Overexposure for large area pattern

Combination with OM photos



- no residual at the corner, usually the base dose is about 1.5x dose to clear.

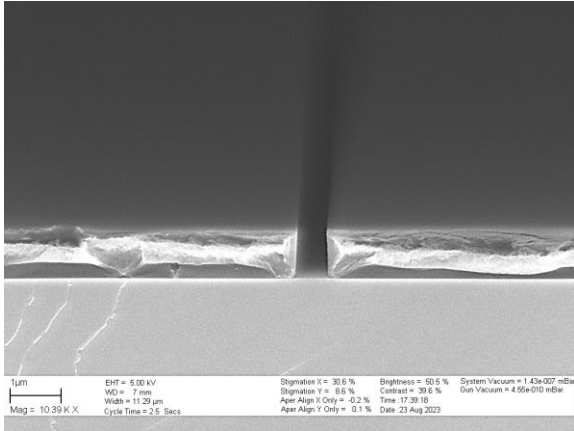
Calibration of PMMA 950K on InP with 2 nA on InP



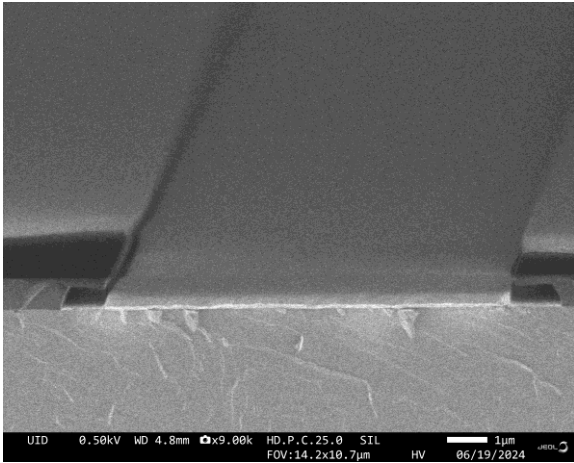
Design:
Line 75 nm, square 232 nm
Measurement:
Line 74 nm, square 236 nm

Photoresist for Lift-Off

Bi-Layer for Lift-Off

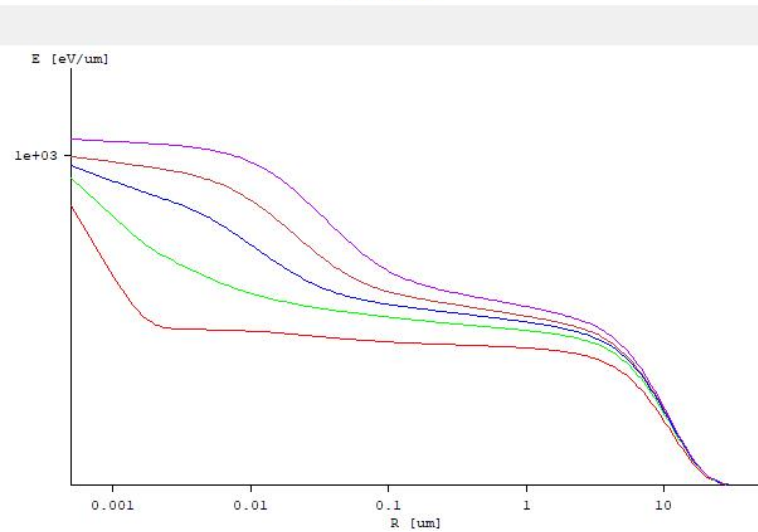
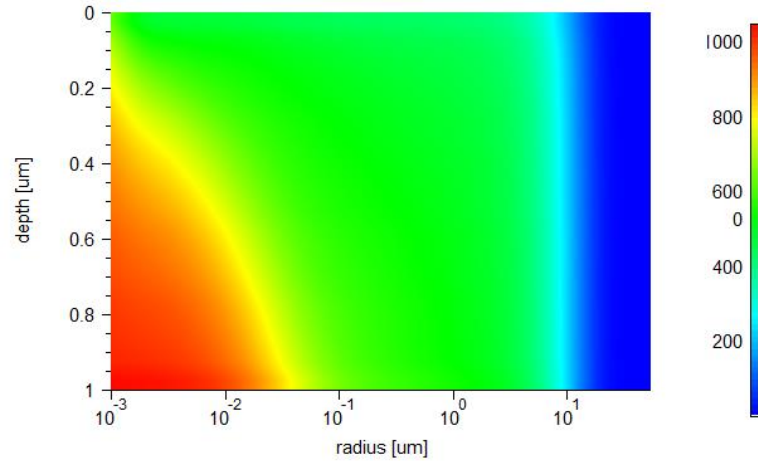


PMMA950K on PMMA600k, 500 nm CD design

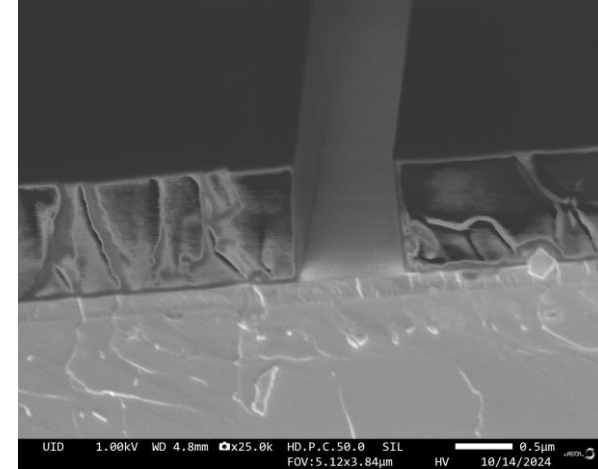


PMMA950K on PMGI with metal deposition, 10 µm CD design

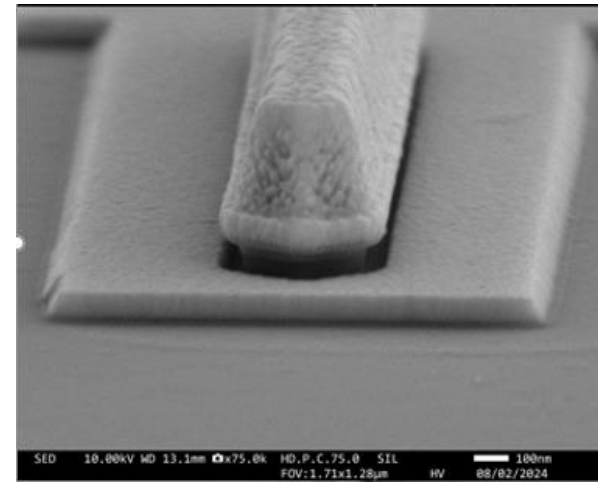
Thick single layer for Lift-Off



Z-dependent absorbed energy in CSAR18 on InP



AR-P 6200.18 (CSAR18) on InP, 500 nm CD design



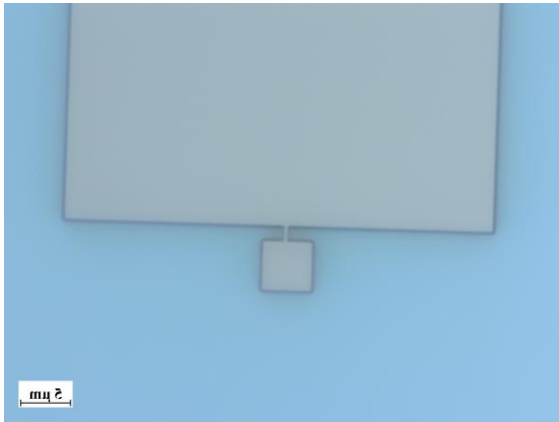
Thin metal deposition with single layer CSAR18

Photoresist for InP/InGaAs Etching

Issue 1: residuls at large pattern edge



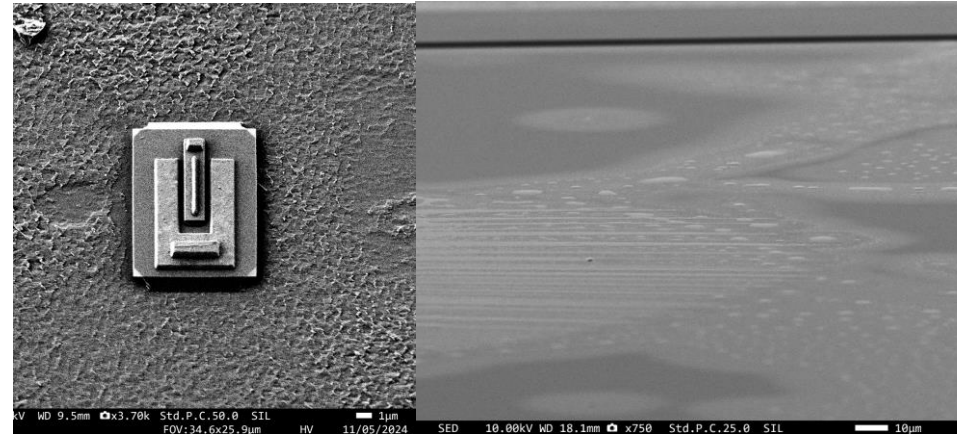
Dose: 180 μC/cm² Development: maD525 for 275 sec.



Dose: 200 μC/cm² Development: maD525 for 180 sec.

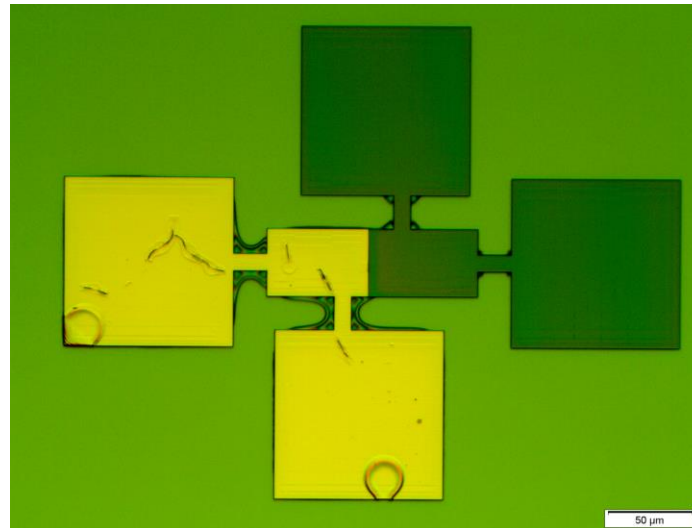
❖ Improvement: Lower dose, longer development

Issue 2: etching residual at surface



❖ Improvement: higher pre-bake temperature

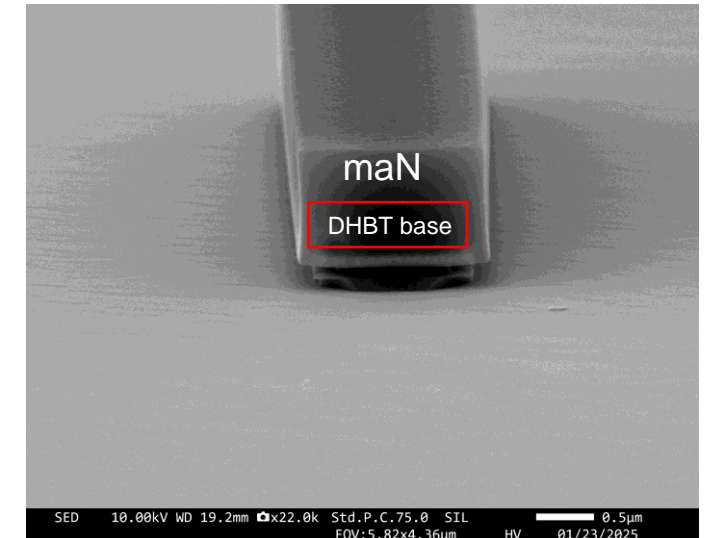
Issue 3: application on metal



❖ Improvement: using 3D Topo PEC in Beamer

For InGaAs/InP etching:

- maN about 5-10 nm thinner than without etching
- A very thin layer formed on the wafer surface
- Thin layer easy removed with acetone
- InP under thin layer are not cleared



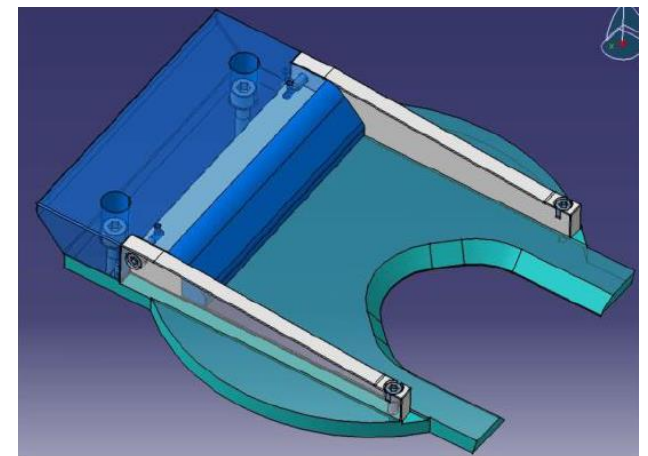
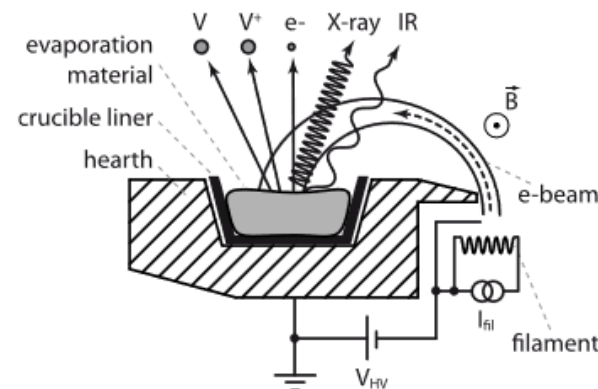
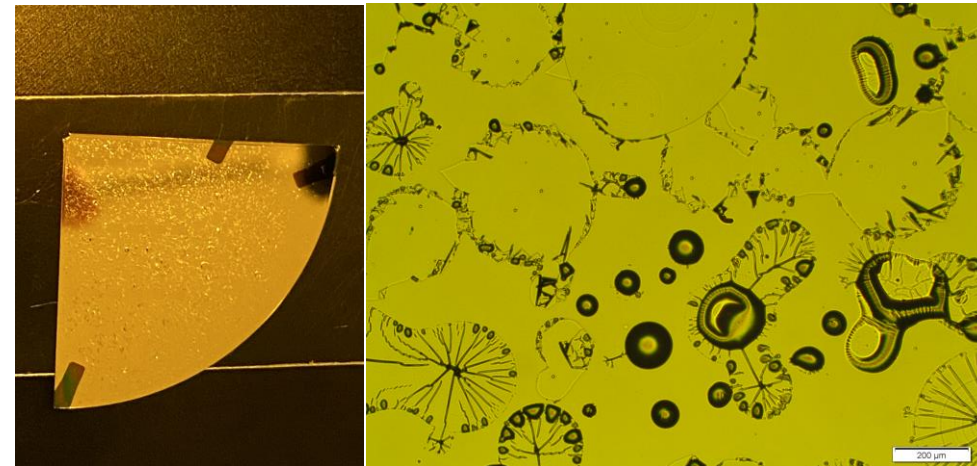
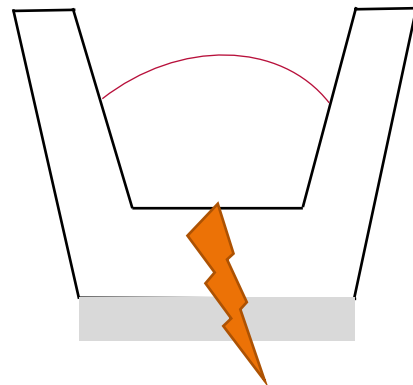
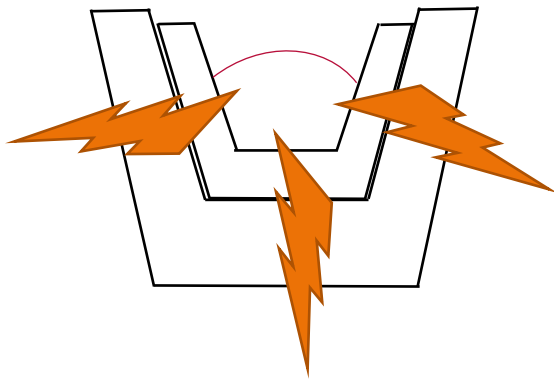
Issues with Metal Deposition: Carbon Contamination

Contamination in metal using carbon based crucible

- Replacement of carbon based crucible with metal based one, like Mo
- Crucible in crucible: 7-8 cc in 12 cc
- Thin spacer at the bottom

Bubbles in PMMA after e-beam evaporation

- Strong CO₂ signal (RGA) observed during Pt evaporation
- Could fixed with a maget kit
- Or PMGI underneath PMMA



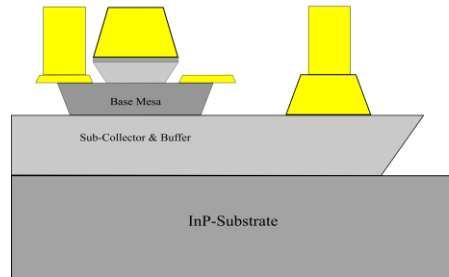
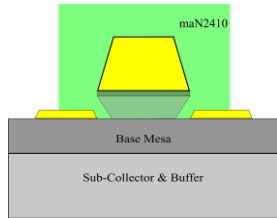
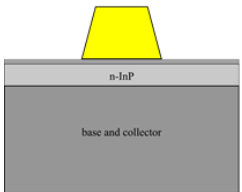
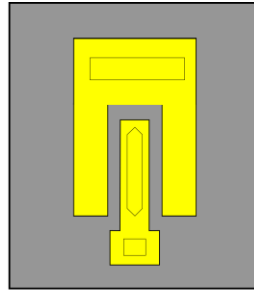
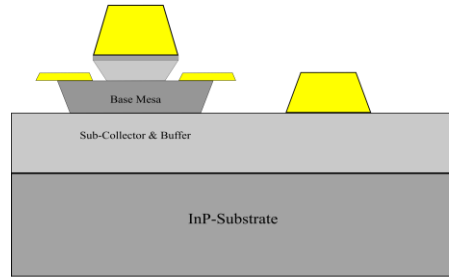
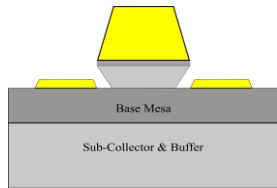
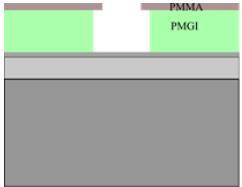
250 nm DHBT Fabrication-Application with 3D Topo PEC

Emitter

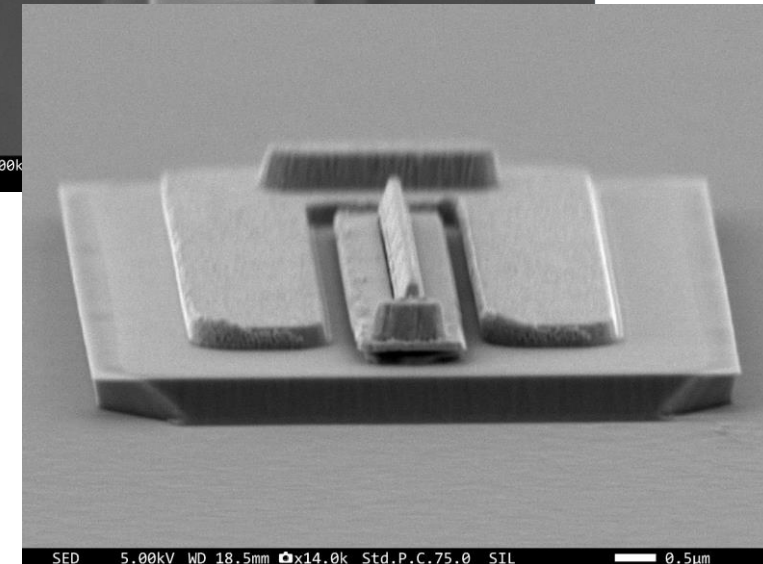
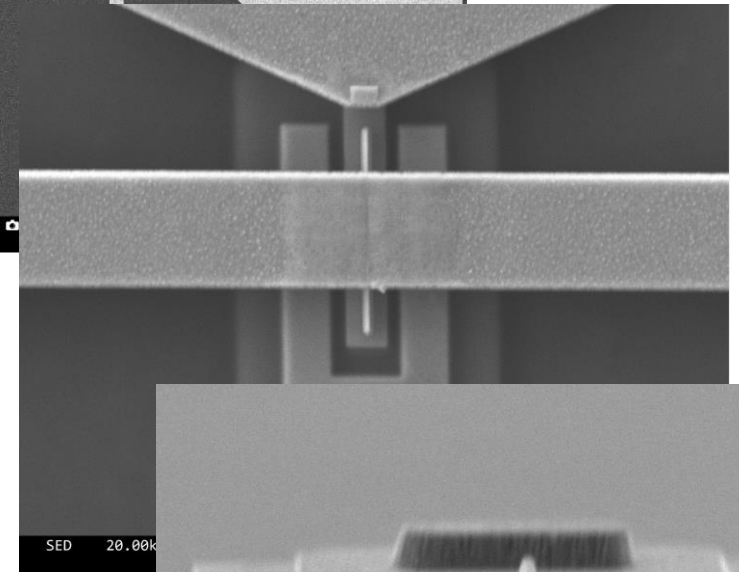
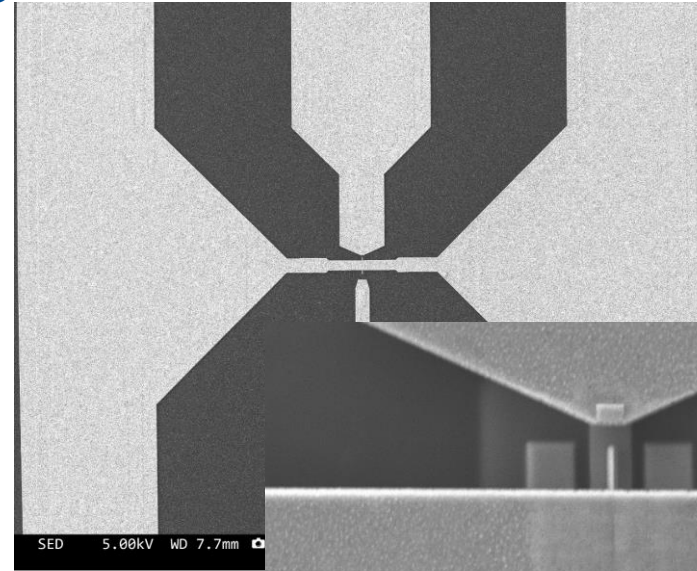
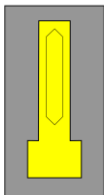
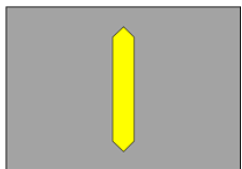
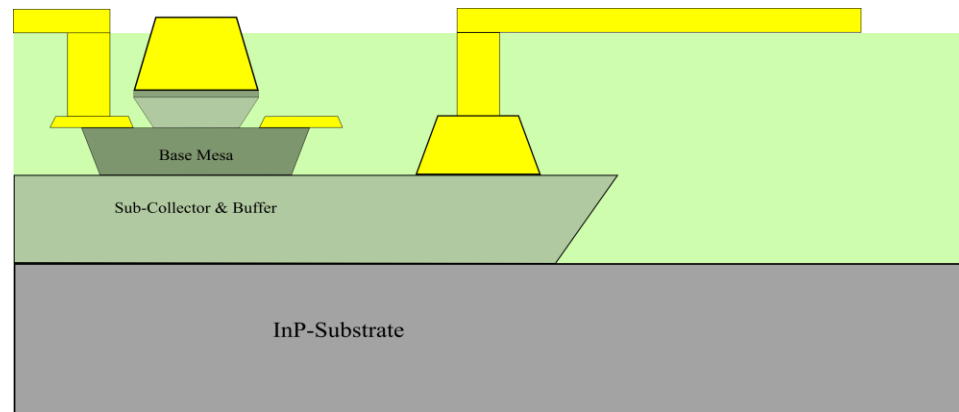
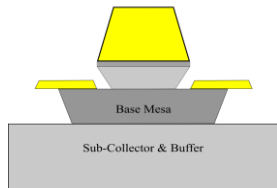
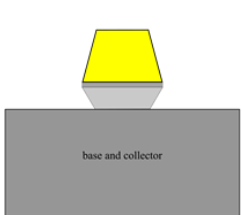
Base

Collector

Planarization



Planarization



A story about how to build a THz device using 100 kV EBL

For department, we are looking for:

- Scientific collaboration for advanced nanofabrication (BMBF& SFB project)
- Industrial collaboration for THz device fabrication and application

For myself, I am looking for:

- Scientific work as a post-doctoral researcher or
- Industrial work like engineer/manager

E-Mail: hao.zhang@uni-due.de



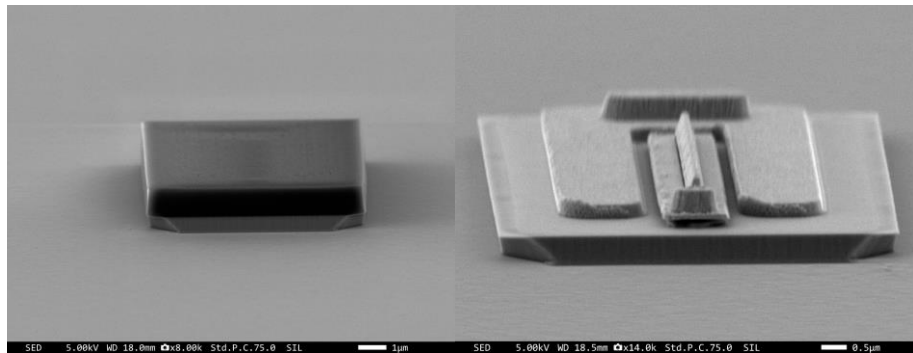
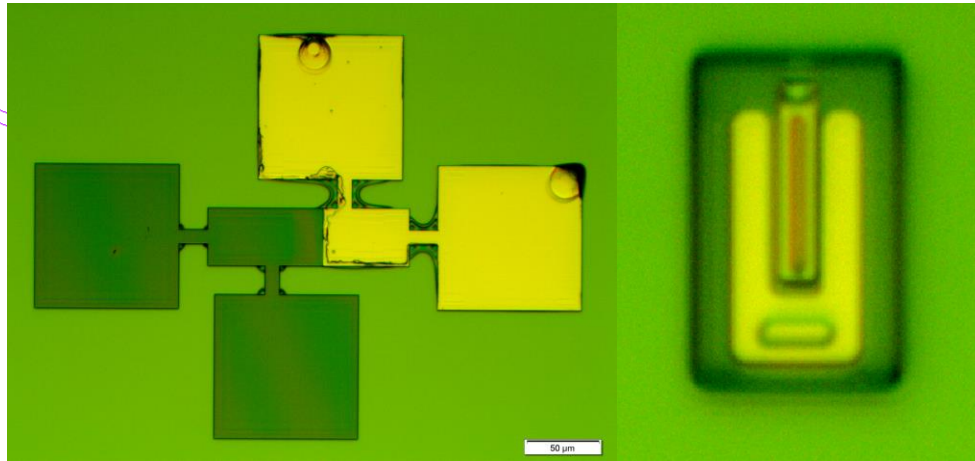
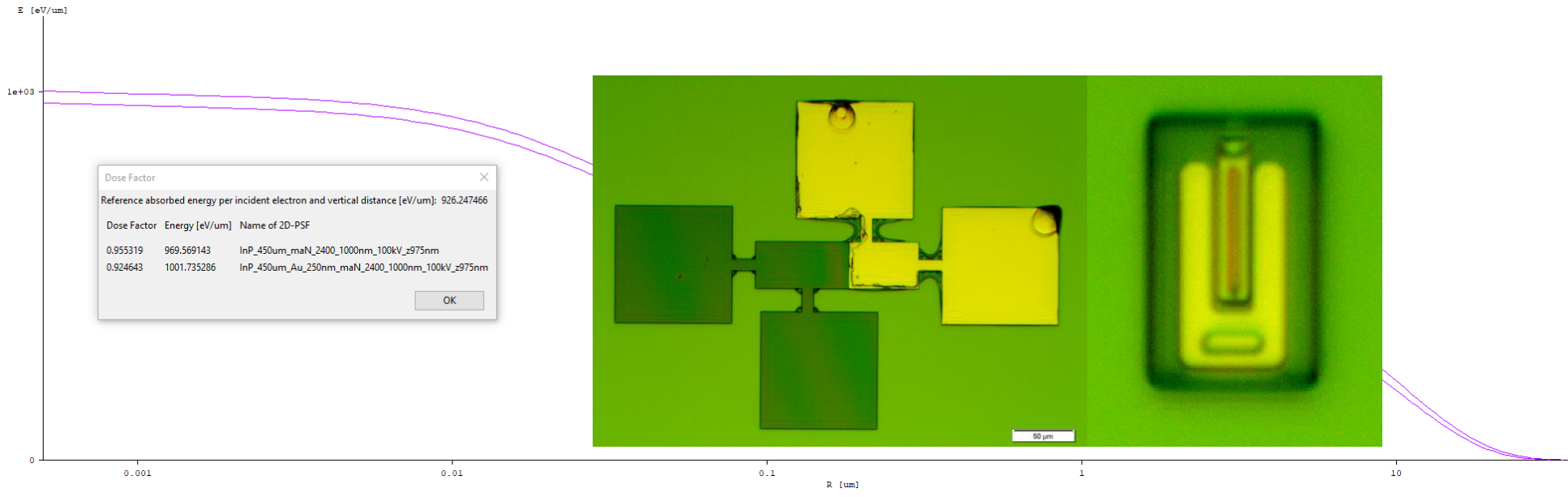
Thank you for your attention!

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Fabrication Process for DHBT

3D PEC



Gray-Scale Application for InP based DHBT